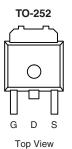
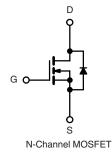


N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R_{DS(on)} (Ω)	I _D (A) ^{a, g}	Q _g (Typ.)			
30	0.0041 at V _{GS} = 10 V	60 ^g	34 nC			
	0.0059 at V _{GS} = 4.5 V	60 ^g	34 110			





FEATURES

- Halogen-free
- TrenchFET[®] Gen III Power MOSFET
- 100 % Rg Tested
- 100 % Avalanche Tested

APPLICATIONS

- Low-Side Switch for DC/DC Converters
 - Servers
 - POL
 - VRM
- OR-ing

ABSOLUTE MAXIMUM RATINGS	T _A = 25 °C, unles	ss otherwise not	ed	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	± 20	v
	T _C = 25 °C		60 ^g	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C		60 ^g	
Continuous Brain Current (1j = 150°C)	T _A = 25 °C	I _D	36 ^{b, c}	
	T _A = 70 °C		29 ^{b, c}	A
Pulsed Drain Current	I _{DM}	80	A	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	60 ^g	
Continuous Source-Drain Diode Current	T _A = 25 °C	'S	4.9 ^{b, c}	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	50	
Single Pulse Avalanche Energy	L = 0.1 mm	E _{AS}	125	mJ
	T _C = 25 °C		83	
Maximum Power Dissipation	T _C = 70 °C	P _D	53	w
	T _A = 25 °C	'D	5.4 ^{b, c}	V
	T _A = 70 °C		3.4 ^{b, c}	
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 150		
Soldering Recommendations (Peak Temperature)			260	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient	t ≤ 10 s	R _{thJA}	18	23	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	1.0	1.5	0/11	

Notes:

a. Based on $T_C = 25 \text{ °C}$. b. Surface Mounted on 1" x 1" FR4 board.

c. t = 10 s.

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Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	s/T i		28			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6.6		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	1.2		2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zana Oata Maltana Duain Ourmant		$V_{DS} = 30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μA	
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 30$ V, $V_{GS} = 0$ V, $T_{J} = 55$ °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	30			А	
		V _{GS} = 10 V, I _D = 20 A		0.0031	0.0041	Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 20 A		0.0043	0.0059		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 10 V, I _D = 20 A		100		S	
Dynamic ^b							
Input Capacitance	C _{iss}			4590			
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		810		pF	
Reverse Transfer Capacitance	C _{rss}			320			
Total Gate Charge		V _{DS} = 15 V, V _{GS} = 10 V, I _D = 20 A		74	110	nC	
	Qg			34	51		
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, \text{ V}_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 20 \text{ A}$		12			
Gate-Drain Charge	Q _{gd}			10			
Gate Resistance	R _g	f = 1 MHz	0.2	0.8	1.6	Ω	
Turn-On Delay Time	t _{d(on)}			19	35		
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.5 Ω		5	10	-	
Turn-Off Delay Time	t _{d(off)}	$\text{I}_\text{D} \cong$ 10 A, V_GEN = 10 V, R_g = 1 Ω		45	85		
Fall Time	t _f			5	10		
Turn-On Delay Time	t _{d(on)}			45	85	ns	
Rise Time	t _r	V_{DD} = 10 V, R_{L} = 1 Ω		18	45	-	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10$ Å, $V_{GEN} = 4.5$ V, $R_g = 1$ Ω		60	110		
Fall Time	t _f			30	60		
Drain-Source Body Diode Characteristic	cs						
Continuous Source-Drain Diode Current	ا _S	T _C = 25 °C			60	•	
Pulse Diode Forward Current ^a	I _{SM}				80	A	
Body Diode Voltage	V _{SD}	I _S = 4 A		0.72	1.1	V	
Body Diode Reverse Recovery Time	t _{rr}			33	50	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			25	40	nC	
Reverse Recovery Fall Time	t _a	$I_F = 10 \text{ A}, \text{ dl/dt} = 100 \text{ A/}\mu\text{s}, \text{ T}_J = 25 ^\circ\text{C}$		16			
Reverse Recovery Rise Time	t _b	-		17		ns	

Notes:

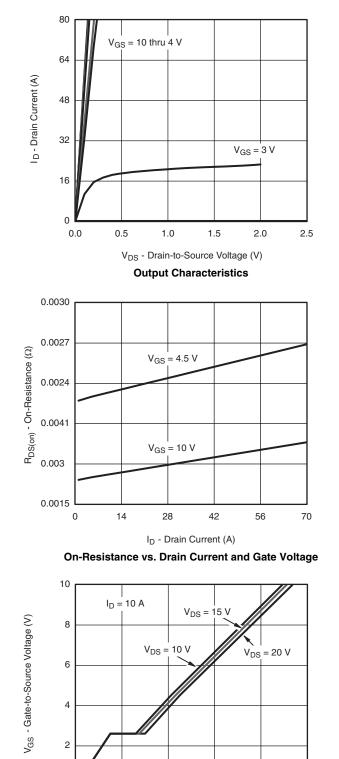
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %. b. Guaranteed by design, not subject to production testing.

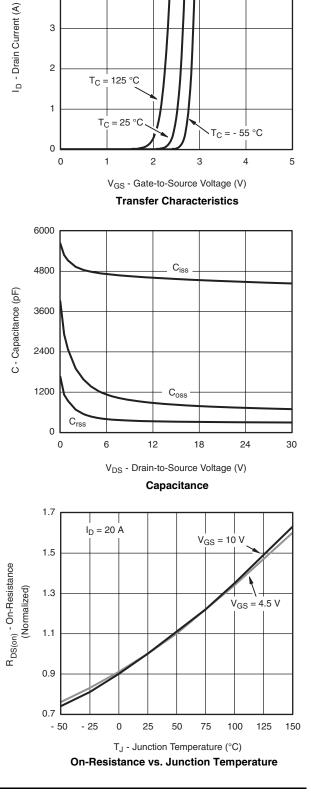
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Qg - Total Gate Charge (nC)

Gate Charge

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

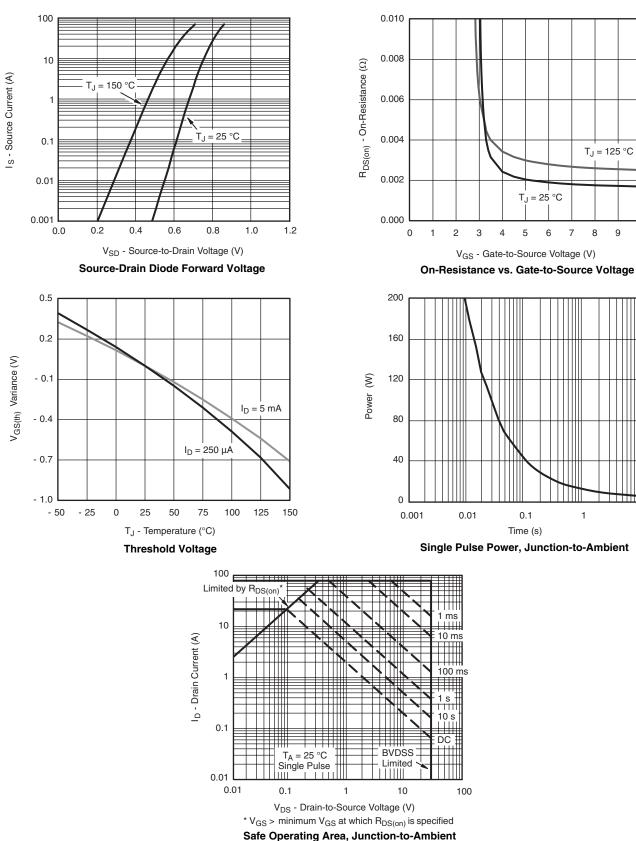




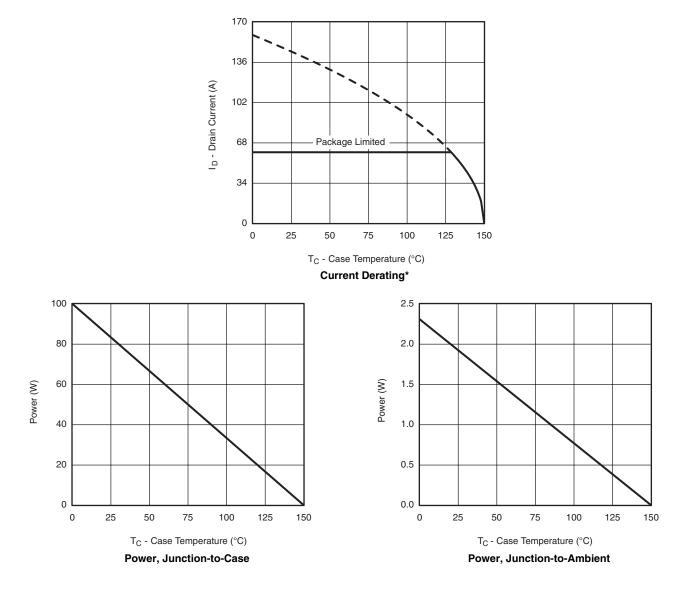
10

10

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

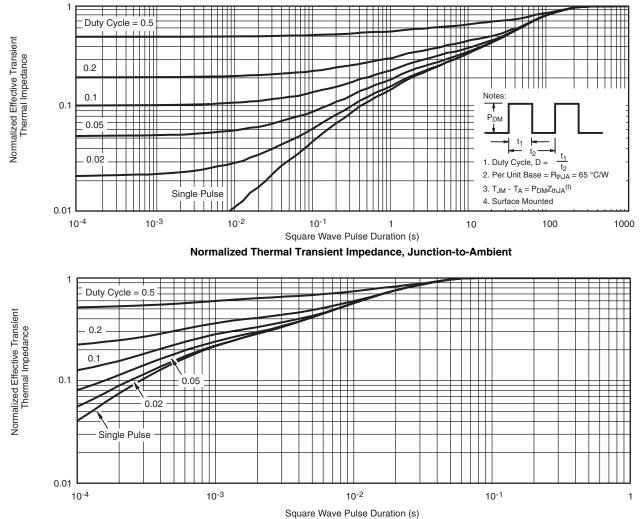


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



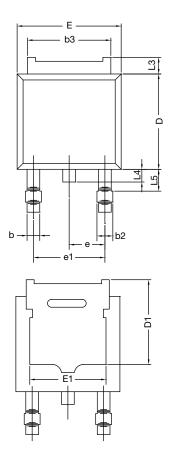
* The power dissipation P_D is based on $T_{J(max)} = 150 \text{ °C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

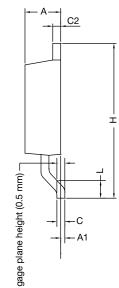
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Case

TO-252AA CASE OUTLINE





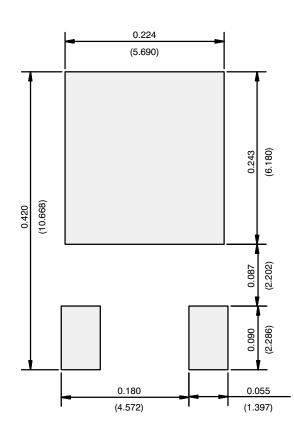
	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	2.18	2.38	0.086	0.094	
A1	-	0.127	-	0.005	
b	0.64	0.88	0.025	0.035	
b2	0.76	1.14	0.030	0.045	
b3	4.95	5.46	0.195	0.215	
С	0.46	0.61	0.018	0.024	
C2	0.46	0.89	0.018	0.035	
D	5.97	6.22	0.235	0.245	
D1	5.21	-	0.205	-	
Е	6.35	6.73	0.250	0.265	
E1	4.32	-	0.170	-	
Н	9.40	10.41	0.370	0.410	
е	2.28 BSC		0.090 BSC		
e1	4.56 BSC		0.180 BSC		
L	1.40	1.78	0.055	0.070	
L3	0.89	1.27	0.035	0.050	
L4	-	1.02	-	0.040	
L5	1.14	1.52	0.045	0.060	
ECN: X12-0247-Rev. M, 24-Dec-12 DWG: 5347					

Note

• Dimension L3 is for reference only.

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RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)



Recommended Minimum Pads Dimensions in Inches/(mm)

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